SLOVENSKI STANDARD
SIST EN 60512-26-100:2008/A1:2011

01-junij-2011

Konektorji za elektronsko opremo - Preskušanje in meritve - 26-100. del: Merilna postavitev, določitev preskusov in referenc ter meritve konektorjev v skladu z IEC 60603-7 - Preskusi od 26a do 26g - Dopolnilo A1 (IEC 60512-26-100:2008/A1:2011)

Connectors for electronic equipment - Tests and measurements - Part 26-100: Measurement setup, test and reference arrangements and measurements for connectors according to IEC 60603-7 - Tests 26a to 26g (IEC 60512-26-100:2008/A1:2011)

Steckverbinder für elektronische Einrichtungen - Mess- und Prüfverfahren - Teil 26-100: Messaufbau, Prüf- und Referenzanordnung und Messverfahren für Steckverbinder nach IEC 60603-7 - Prüfungen 26a bis 26g (IEC 60512-26-100:2008/A1:2011)

Connecteurs pour équipements électroniques - Essais et mesures - Partie 26-100: Montage de mesure, dispositifs d'essai et de référence et mesures pour les connecteurs conformes à la CEI 60603-7 - Essais 26a à 26g (CEI 60512-26-100:2008/A1:2011)

Ta slovenski standard je istoveten z: **EN 60512-26-100:2008/A1:2011**

ICS:

31.220.10	Vtiči in vtičnice, konektorji	Plug-and-socket devices. Connectors

SIST EN 60512-26-100:2008/A1:2011 **en**

EUROPEAN STANDARD

NORME EUROPÉENNE

EUROPÄISCHE NORM

EN 60512-26-100/A1

April 2011

ICS 13.220.10

English version

Connectors for electronic equipment - Tests and measurements - Part 26-100: Measurement setup, test and reference arrangements and measurements for connectors according to IEC 60603-7 - Tests 26a to 26g

(IEC 60512-26-100:2008/A1:2011)

Connecteurs pour équipements électroniques - Essais et mesures - Partie 26-100: Montage de mesure, dispositifs d'essai et de référence et mesures pour les connecteurs conformes à la CEI 60603-7 - Essais 26a à 26g

(CEI 60512-26-100:2008/A1:2011)

Steckverbinder für elektronische Einrichtungen - Mess- und Prüfverfahren - Teil 26-100: Messaufbau, Prüf- und Referenzanordnung und Messverfahren für Steckverbinder nach IEC 60603-7 - Prüfungen 26a bis 26g

(IEC 60512-26-100:2008/A1:2011)

This amendment A1 modifies the European Standard EN 60512-26-100:2008; it was approved by CENELEC on 2011-04-18. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Management Centre: Avenue Marnix 17, B - 1000 Brussels

Foreword

The text of document 48B/2065/CDV, future amendment 1 to IEC 60512-26-100:2008, prepared by SC 48B, Connectors, of IEC TC 48, Electromechanical components and mechanical structures for electronic equipment, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as amendment A1 to EN 60512-26-100:2008 on 2011-04-18.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN and CENELEC shall not be held responsible for identifying any or all such patent rights.

The following dates were fixed:

– latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement	(dop)	2012-01-18
– latest date by which the national standards conflicting with the amendment have to be withdrawn	(dow)	2014-04-18

Endorsement notice

The text of amendment 1:2011 to the International Standard IEC 60512-26-100:2008 was approved by CENELEC as an amendment to the European Standard without any modification.

IEC 60512-26-100

Edition 1.0 2011-03

INTERNATIONAL STANDARD

NORME INTERNATIONALE

AMENDMENT 1
AMENDEMENT 1

Connectors for electronic equipment – Tests and measurements – Part 26-100: Measurement setup, test and reference arrangements and measurements for connectors according to IEC 60603-7 – Tests 26a to 26g

Connecteurs pour équipements électroniques – Essais et mesures – Partie 26-100: Montage de mesure, dispositifs d'essai et de référence et mesures pour les connecteurs conformes à la CEI 60603-7 – Essais 26a à 26g

INTERNATIONAL ELECTROTECHNICAL COMMISSION

COMMISSION ELECTROTECHNIQUE INTERNATIONALE

PRICE CODE
CODE PRIX
D

ICS 13.220.10
ISBN 978-2-88912-410-7

FOREWORD

This amendment has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

The text of this amendment is based on the following documents:

FDIS	Report on voting
48B/2065/FDIS	48B/2149/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

4.5.4.2 Triaxial set-up

Replace the existing third paragraph by the following:

R_1 is the inner circuit terminating load and is chosen to be within ± 2 % of Z_1, the inner circuit impedance (see 4.5.4.3.2), utilising one or more standard value resistors.

R_2 is the outer circuit terminating load and is chosen to be within ± 2 % of the value, utilizing one or more standard value resistors, determined according to

$$R_2 = Z_2 - 50$$

where Z_2 is the outer circuit impedance (see 4.5.4.3.3).

4.5.4.3 Impedance of the inner circuit

Replace the existing title and text by the following:

4.5.4.3 Inner and outer circuit impedances

4.5.4.3.1 General

Where the inner circuit impedance (Z_1) or outer circuit impedance (Z_2) are unknown, the inner circuit impedance shall be determined according to 4.5.4.3.2 and the outer circuit impedance shall be determined according to 4.5.4.3.3.

Measurements shall be made by preparing the sample (for the inner circuit impedance measurement) or the sample in the metallic tube (for the outer circuit impedance measurement), and connecting to a network analyzer (or other suitable measurement system) which has been calibrated for impedance measurements at the sample or metallic tube reference planes respectively. The test frequency shall be the approximate frequency for which the length of the sample is $\frac{1}{8}\ \lambda$, where λ is the wavelength.

$$f_{\text{test}} \sim \frac{c}{1{,}5 \times 8 \times L_{\text{sample}}}$$

where

f_{test} is the test frequency

c is the speed of light

L_{sample} is the length of the sample

4.5.4.3.2 Inner circuit impedance measurement

The short circuit inner circuit impedance ($Z_{1\ \text{short}}$) is measured by short circuiting the far end of the prepared sample.

The open circuit inner circuit impedance ($Z_{1\ \text{open}}$) is measured by leaving the far end of the prepared sample open at the same point where it was shorted for the short circuit inner impedance measurement.

The inner circuit impedance is calculated as:

$$Z_1 = \sqrt{Z_{1\,\text{short}} \times Z_{1\,\text{open}}}$$

4.5.4.3.3 Outer circuit impedance measurement

The outer circuit impedance is measured from port 2 of the network analyzer with the outer circuit terminating load (R_2) set to zero, i.e. short circuit (see Figure 12).

The short circuit outer circuit impedance ($Z_{2\ \text{short}}$) is measured by short circuiting the far end of the metallic tube to the screen of the prepared sample (as shown in Figure 12).

The open circuit outer circuit impedance ($Z_{2\ \text{open}}$) is measured by leaving the far end of the metallic tube “open” to the screen of the prepared sample at the same point where it was shorted for the short circuit outer impedance measurement. It is recommended that the

prepared sample be held in place using a low dielectric insulating support inside the metallic tube in approximately the same spatial position that it will occupy during the transfer impedance measurement.

The outer circuit impedance is calculated as:

$$Z_2 = \sqrt{Z_{2\,\text{short}} \times Z_{2\,\text{open}}}$$